

CLAIM AMENDMENTS

1. (currently amended) A sample ~~holding-substrate~~ holder for use with an infrared spectrophotometer or infrared filterometer that analyzes a sample through which infrared light is transmitted comprising a mounting means comprised of a first material having an aperture formed therein, an infrared light transmitting sample supporting substrate being present in the aperture comprised of a second material ~~window~~ allowing infrared light to pass therethrough without the infrared light transmitting sample supporting substrate or any other material within the aperture substantially absorbing ~~allowing substantial absorption of infrared light within a substantial portion of the infrared spectral range~~, said infrared light transmitting sample supporting substrate being formed by one or more of the steps comprising cleaving, fly cutting, chipping, milling, sawing or scaling and wherein said infrared light transmitting sample supporting substrate has not been precision optically polished.

2. (currently amended) The sample ~~holding-substrate~~ holder as defined in claim 1 wherein the infrared light transmitting sample supporting substrate ~~window~~ is mounted in a the holder ~~with at least one clear aperture~~ such that the perimeter of the aperture frames all or a centrally located part of said infrared light transmitting sample supporting substrate ~~window~~ to form an unimpeded path for infrared light to pass through the infrared light transmitting sample supporting substrate ~~at least one clear aperture and the window~~.

Claims 3-9. (canceled)

10. (currently amended) The sample ~~holding-substrate~~ holder as defined in claim 1 wherein said infrared light transmitting sample supporting substrate ~~window~~ is an alkali halide crystal.

11. (currently amended) The sample ~~holding-substrate~~ holder as defined in claim 1 wherein said infrared light transmitting sample supporting substrate ~~window~~ is an alkali halide crystal selected from the group consisting of KBr, NaCl and KCl.

12. (currently amended) The sample ~~holding-substrate~~ holder as defined in claim 1 wherein said infrared light transmitting sample supporting substrate window is comprised of a silica material.

13. (currently amended) The sample ~~holding-substrate~~ holder as defined in claim 1 wherein said infrared light transmitting sample supporting substrate window is comprised of a glass composition of germanium, arsenic and selenium.

14. (currently amended) The sample ~~holding-substrate~~ holder as defined in claim 1 wherein said infrared light transmitting sample supporting substrate window is comprised of a glass composition of germanium, antimony and selenium.

15. (currently amended) The sample ~~holding-supporting-substrate window~~ holder as defined in claim 2 further having an infrared light transmitting cover slide window formed by one or more of the steps comprising cleaving, fly cutting, chipping, milling, sawing or scaling.

16. (currently amended) The sample ~~holding-substrate~~ holder as defined in claim 15 wherein a spacer is located between said infrared light transmitting sample supporting substrate window and said infrared light transmitting cover slide window to create a predetermined space therebetween.

17. (currently amended) The sample ~~holding-substrate~~ holder as defined in claim 15 wherein said infrared light transmitting cover slide window is affixed to said infrared light transmitting sample supporting substrate window by a clamping means.

18. (currently amended) A method for the manufacture of a sample ~~holding-substrate~~ holder for use in an infrared spectrophotometer or infrared filterometer, said method comprising the steps of:

providing a mounting means comprised of a first material having an aperture therethrough;

providing an infrared light transmitting material,

forming an infrared light transmitting sample supporting substrate of a second material window having infrared light transmissive properties such that the substrate does surfaces that ~~do~~ not substantially absorb infrared light within a substantial portion of the infrared spectral range, said infrared light transmitting sample supporting substrate being formed by cleaving, fly cutting, chipping, milling, sawing or scaling material from said infrared light transmitting material without precision optical polishing of the infrared light transmitting material transmissive surfaces to form a an infrared light transmitting sample supporting substrate window that allows the passage of infrared light therethrough;

positioning the infrared light transmitting sample supporting substrate within the aperture so as to allow infrared light to pass through the aperture and the infrared light transmitting sample supporting substrate and with no other material within the aperture that absorbs infrared light.

19. (currently amended) A method for the manufacture of a sample ~~holding~~ substrate holder as defined in claim 20 wherein said step of providing a mounting means having an aperture ~~holder~~ comprises providing a disposable card holder or demountable card holder.

20. (currently amended) A method for the manufacture of a sample ~~holding-substrate~~ holder as defined in claim 18 further including the step steps of:

~~providing a holder having at least one aperture formed therein, said holder being formed so as to be capable of orienting the sample holding substrate in the path of the infrared light transmitted by an infrared spectrophotometer or filterometer, and~~

mounting the infrared light transmitting sample supporting substrate window to the holder in a position wherein all or a centrally located part of the infrared light transmitting sample supporting substrate window is framed by the perimeter of said ~~at least one~~ aperture.

Claims 21-27. (canceled)

28. (currently amended) A method for the manufacture of a sample ~~holding~~ substrate holder as defined in claim 18 further including the step of affixing a an infrared light

transmitting cover slide window to the infrared light transmitting sample supporting substrate
~~sample holding card~~ to provide a means of sandwiching a sample between said infrared light
transmitting cover slide window and said infrared light transmitting sample supporting
substrate window.

29. (canceled)

30. (currently amended) A method for using a sample ~~holding substrate~~ holder in an infrared spectrophotometer or infrared filterometer having an infrared light source and an infrared light detector, said method comprising the steps of:

providing an infrared light transmitting material,

providing an infrared light transmitting sample supporting substrate comprised of a first material window having infrared light transmissive properties such that the infrared light transmitting substrate does ~~surfaces that do~~ not substantially absorb infrared light within a substantial portion of the infrared spectral range, said infrared light transmitting sample supporting substrate being formed by cleaving, fly cutting, chipping, milling, sawing or scaling the ~~window~~ infrared light transmitting sample supporting substrate from said infrared light transmitting material without precision optical polishing of the infrared light transmitting sample supporting substrate transmissive surfaces,

providing a mounting means comprised of a second material holder having at least one aperture adapted to fit within the spectrophotometer or filterometer, said mounting means holder being formed so as to be capable of orienting the infrared light transmitting sample supporting ~~holding~~ substrate in the path of the infrared light emitted by an infrared spectrophotometer or filterometer,

mounting the infrared light transmitting sample supporting substrate window to the mounting means holder in a position where all or a centrally located part of the infrared light transmitting sample supporting substrate window is framed by the perimeter of the at least one aperture aperture,

placing a sample to be analyzed onto the infrared light transmitting sample supporting substrate window,

inserting the holder into the spectrophotometer or filterometer between the infrared light source and the infrared light detector with the at least one aperture ~~at least one aperture~~ aligned with the infrared light emitted by the infrared light source to allow the passage of ~~a beam of~~ infrared light ~~energy~~ through the sample, the infrared light transmitting sample supporting substrate window and the aperture and no other material within said aperture other than the sample that absorbs infrared light.

31. (currently amended) A method as defined in claim 30 wherein said step of providing a mounting means ~~holder~~ comprises providing a card ~~holder~~ made of a disposable material.

32. (previously presented) A method as defined in claim 31 wherein said step of providing an infrared light transmitting material comprises providing an alkali halide crystal material.

33. (previously presented) A method as defined in claim 32 wherein said step of providing an infrared light transmitting material comprises providing a material selected from the group consisting of KBr, NaCl and KCl

34. (canceled)

35. (currently amended) A method as defined in claim 31 wherein said step of providing a mounting means ~~holder~~ further comprises the step of affixing an infrared light transmitting cover slide window ~~having infrared light transmissive surfaces~~ to the infrared light transmitting sample supporting substrate window to form a means of sandwiching a sample between said infrared light transmitting cover slide window and said infrared light transmitting sample supporting substrate window, said infrared light transmitting cover slide window being formed by one or more of the steps comprising cleaving, fly cutting, chipping, milling, sawing or scaling without precision optical polishing of the infrared light transmitting cover slide window ~~transmissive surfaces~~.

36. (currently amended) A method as defined in claim 35 wherein said step of placing a sample to be analyzed comprises sandwiching the sample between the infrared light transmitting cover slide window and the infrared light transmitting sample supporting substrate window.

37. (currently amended) A method as defined in claim 36 wherein said step placing a sample to be analyzed comprises placing a bacterial colony between said infrared light transmitting cover slide window and said infrared light transmitting sample supporting substrate window.

38. (canceled)

39. (currently amended) A method for using a sample ~~holding-substrate~~ holder for use in an infrared spectrophotometer or infrared filterometer having an infrared light source and an infrared light detector, said method comprising the steps of:

providing a mounting means comprised of a first material holder having a plurality of apertures adapted to fit within said infrared spectrophotometer or infrared filterometer, said mounting means holder being formed so as to be capable of orienting the apertures sample holding-substrate in the path of the infrared light emitted by an infrared spectrophotometer or filterometer,

providing an infrared light transmitting material,

forming a plurality of infrared light transmitting sample supporting substrates comprised of a second material windows-having infrared light transmissive properties such that the substrate does surfaces that do not substantially absorb infrared light within a substantial portion of the infrared spectral range, said infrared light transmitting sample supporting substrate being formed by cleaving, fly cutting, chipping, milling, sawing or scaling said infrared light transmitting sample supporting substrates windows from said light transmitting material without precision optical polishing of the infrared light transmitting sample supporting substrates transmissive surfaces,

mounting one of said plurality of said infrared light transmitting sample supporting substrates windows to the mounting means holder in a position wherein all or a centrally

located part of one of said infrared light transmitting sample supporting substrates windows is framed by the perimeter of at least one of the apertures,

placing a sample to be analyzed onto at least one of the infrared light transmitting sample supporting substrates windows,

inserting the holder having the infrared light transmitting sample supporting substrate mounted thereto into said infrared spectrophotometer or infrared filterometer between the infrared light source and the infrared light detector with ~~the~~ at least one of the apertures aperture aligned with the infrared light emitted by the infrared light source to allow the passage of a beam of infrared light through one or more samples, said infrared light transmitting sample supporting substrates windows and apertures and no other material other than the sample within said aperture that absorbs infrared light.

40. (currently amended) A method for using a sample ~~holding-substrate~~ holder as defined in claim 39 wherein said step of forming a plurality of apertures and infrared light transmitting sample supporting substrates windows mounted thereon comprises forming the plurality of apertures and infrared light transmitting sample supporting substrates windows in a carousel configuration.

41. (currently amended) A method for using a sample ~~holding-substrate~~ holder as defined in claim 40 wherein said step of placing a sample to be analyzed comprises placing a plurality of samples onto said plurality of infrared light transmitting sample supporting substrates windows and said infrared spectrophotometer or infrared filterometer passes infrared light sequentially through said plurality of samples, said infrared light transmitting sample supporting substrates windows and said apertures and no other material within said apertures that absorbs infrared light.

42. (currently amended) A method for using a sample ~~holding-substrate~~ holder as defined in claim 40 wherein said step of placing a sample onto at least one of the infrared light transmitting sample supporting substrates windows comprises placing a bacterial colony onto said at least one infrared light transmitting sample supporting substrate window.

43. (currently amended) A method for using a sample ~~holding-substrate~~ holder as defined in claim 40 wherein said step of inserting the holder having the infrared light transmitting sample supporting substrate mounted thereto into the infrared spectrophotometer or infrared filterometer comprises inserting the holder in a horizontal position within the infrared spectrophotometer or infrared filterometer and passing a beam of infrared light at least once through the sample, the infrared light transmitting sample supporting substrates ~~windows~~ and the aperture.

44. (currently amended) A method for using a sample ~~holding-substrate~~ holder as defined in claim 43 wherein the beam of infrared light is passed at least once through the sample by means of reflection.

45. (currently amended) A method for using a sample ~~holding-substrate~~ holder for use in an infrared spectrophotometer or infrared filterometer having an infrared light source and an infrared light detector, said method comprising the steps of:

providing a plurality of mounting means comprised of a first material ~~holders~~, each having at least one aperture, each of said mounting means ~~holders~~ being formed so as to be capable of orienting the at least one aperture ~~sample-holding-substrate~~ in the path of the infrared light emitted by an infrared spectrophotometer or filterometer

providing an infrared light transmitting material,

forming a plurality of infrared light transmitting sample supporting substrates ~~comprised of a second material~~ ~~windows~~ having infrared light transmissive properties such that the infrared light transmitting substrates ~~surfaces that~~ do not substantially absorb infrared light within a substantial portion of the infrared spectral range, said infrared light transmitting sample supporting substrates formed by cleaving, fly cutting, chipping, milling, sawing or scaling infrared light transmitting sample supporting substrates ~~windows~~ from said infrared light transmitting material without precision optical polishing of the infrared light transmitting sample supporting substrates ~~transmissive surfaces~~,

mounting one of said plurality of infrared light transmitting sample supporting substrates ~~windows~~ to each of said plurality of mounting means ~~holders~~ in a position wherein

all or a centrally located part of said sample supporting mounting means ~~holders~~ is framed by the perimeter of the an apertures,

providing a mechanical carousel adapted to fit into the infrared spectrophotometer or infrared filterometer,

mounting said plurality of mounting means ~~holders~~ onto the mechanical carousel,

placing a sample to be analyzed onto at least one of the infrared light transmitting sample supporting substrates ~~windows~~,

inserting the carousel into the infrared spectrophotometer or infrared filterometer between the infrared light source and the infrared light detector with the at least one aperture ~~apertures~~ aligned with the infrared light emitted by the infrared light source to allow the passage of a beam of infrared light in a sequential manner through the plurality of infrared light transmitting sample supporting substrates ~~windows~~, said samples and said apertures and no other material ~~other than the samples within said throughbores that absorb infrared light~~.

46. (currently amended) A method for using a sample ~~holding-substrate~~ holder in an infrared spectrophotometer or infrared filterometer having an infrared light source and an infrared light detector, said method comprising the steps of:

providing an infrared light transmitting material,

providing a an infrared light transmitting sample supporting substrate comprised of a second material ~~window~~ having infrared light transmissive properties such that the infrared light transmitting sample supporting substrate does surfaces that do not substantially absorb infrared light within a substantial portion of the infrared spectral range, said infrared light transmitting sample supporting substrate formed by cleaving, fly cutting, chipping, milling, sawing or scaling the infrared light transmitting sample supporting substrate ~~window~~ from said infrared light transmitting material without precision optical polishing of the infrared light transmitting sample supporting substrate ~~transmissive surfaces~~,

providing a mounting means comprised of a first material ~~holder~~ having at least one aperture adapted to fit within the infrared spectrophotometer or infrared filterometer, said holder being formed so as to be capable of orienting the at least one aperture ~~sample holding-substrate~~ in the path of the infrared light emitted by an infrared spectrophotometer or filterometer,

mounting the infrared light transmitting sample supporting substrate window to the mounting means holder in a position wherein all or a centrally located part of the infrared light transmitting sample supporting substrate window is framed by the perimeter of the at least one aperture,

inserting the holder into the infrared spectrophotometer or infrared filterometer to allow the passage of a beam of infrared light through the infrared light transmitting sample supporting substrate window to obtain one or more background scans of the absorbance of the infrared light transmitting sample supporting substrate,

placing a sample to be analyzed onto the infrared light transmitting sample supporting window substrate,

inserting the holder into the infrared spectrophotometer or infrared filterometer between the infrared light source and the infrared light detector with the at least one aperture aligned with the infrared light emitted by the infrared light source to allow the passage of a beam of infrared light through the infrared light transmitting sample supporting substrate window and the sample located thereon and with no other material within said at least one aperture that absorbs infrared light to obtain a scan of the absorbance of the sample and the infrared light transmitting sample supporting substrate window, and,

using the one or more background scans to subtract the background absorbance of the infrared light transmitting sample supporting substrate window without the sample from the absorbance of the sample and the infrared light transmitting sample supporting substrate window.

47. (currently amended) A method for using a sample ~~holding-substrate~~ holder in an infrared spectrophotometer or infrared filterometer having an infrared light source and an infrared light detector, said method comprising the steps of:

providing an infrared light transmitting material,

providing an infrared light transmitting sample supporting substrate comprised of a second material window having infrared light transmissive properties such that the infrared light transmitting sample supporting substrate does ~~surfaces that do~~ not substantially absorb infrared light within a substantial portion of the infrared spectral range, said infrared light transmitting sample supporting substrate formed by cleaving, fly cutting, chipping, milling,

sawing or scaling the infrared light transmitting sample supporting substrate window from said infrared light transmitting material without precision optical polishing of the infrared light transmitting sample supporting substrate light transmissive surfaces,

providing a mounting means comprised of a first material holder having at least one aperture adapted to fit within the infrared spectrophotometer or infrared filterometer, said mounting means holder being formed so as to be capable of orienting the infrared light transmitting sample supporting holding substrate in the path of the infrared light emitted by the infrared spectrophotometer or filterometer,

mounting the infrared light transmitting sample supporting substrate window to the mounting means holder in a position wherein all or a centrally located part of the infrared light transmitting sample supporting substrate window is framed by the perimeter of the at least one aperture,

placing a medium onto the infrared light transmitting sample supporting substrate window with which a sample will be mixed,

inserting the holder into the infrared spectrophotometer or infrared filterometer to allow the passage of a beam of infrared light through the medium and the infrared light transmitting sample supporting substrate window to obtain one or more background scans of the infrared light transmitting sample supporting substrate window and the medium,

placing a sample to be analyzed mixed with the medium onto the infrared light transmitting sample supporting substrate window,

inserting the holder into the infrared spectrophotometer or infrared filterometer analytical instrument between the infrared light source and the infrared light detector with the at least one aperture aligned with the infrared light emitted by the infrared light source to allow ~~the passage of a beam of~~ infrared light through the infrared light transmitting sample supporting substrate window and the medium mixed with the sample and with no other material other than the sample within said at least one aperture that absorbs infrared light and,

using the one or more background scans to subtract the absorbances of the medium and the infrared light transmitting sample supporting substrate window from the absorbances of the medium, the infrared light transmitting sample supporting substrate window and the sample.

48. (currently amended) A method of using a sample ~~holding-substrate~~ holder as defined in claim 47 wherein said step of placing a medium onto the infrared light transmitting sample supporting substrate window with which the sample will be mixed comprises placing an alkali halide crystal powder on the infrared light transmitting sample supporting substrate window.

49. (currently amended) A method of using a sample ~~holding-substrate~~ holder as defined in claim 48 wherein said step of placing a medium onto the infrared light transmitting sample supporting substrate window with which the sample will be mixed comprises placing KBr powder on the infrared light transmitting sample supporting substrate window.

50. (currently amended) A method of using a sample ~~holding-substrate~~ holder as defined in claim 47 wherein said step of placing a medium onto the infrared transmitting sample supporting substrate window with which the sample will be mixed comprises placing mineral oil on the infrared transmitting sample supporting substrate window.

51. (currently amended) A method of using a sample ~~holding-substrate~~ holder as defined in claim 47 wherein said step of placing a medium onto the infrared light transmitting sample supporting substrate window with which the sample will be mixed comprises placing a solvent on the infrared light transmitting sample supporting substrate window.

52. (currently amended) A method of using a sample ~~holding-substrate~~ holder as defined in claim 47 wherein said step of placing a medium onto the infrared light transmitting sample supporting substrate window with which the sample will be mixed comprises placing a mixture of KBr powder and a solvent or a mineral oil on the infrared light transmitting sample supporting substrate window.

53. (currently amended) A method for using a sample ~~holding-substrate~~ holder in an infrared spectrophotometer or infrared filterometer having an infrared light source and an infrared light detector, said method comprising the steps of:

providing an infrared light transmitting material,

providing an infrared light transmitting sample supporting substrate comprised of second material window having infrared light transmissive properties such that the infrared light transmitting sample supporting substrate does surfaces that do not substantially absorb infrared light within a substantial portion of the infrared spectral range, said infrared light transmitting sample supporting substrate formed by cleaving, fly cutting, chipping, milling, sawing or scaling the infrared light transmitng sample supporting substrate window from said infrared light transmitting material without precision optical polishing of the infrared light transmitting sample supporting substrate ~~transmissive surfaces~~,

providing a mounting means comprised of a first material holder having at least one aperture adapted to fit within the spectrophotometer or filtometer, said mounting means holder being formed so as to be capable of orienting the infrared light transmitting sample supporting holding substrate in the path of the infrared light emitted by an infrared spectrophotometer or filtometer,

mounting the infrared light transmitting sample supporting substrate window to the mounting means holder in a position where all or a centrally located part of the infrared light transmitting sample supporting substrate window is framed by the perimeter of the at least one aperture,

placing a bacterial colony to be analyzed onto the infrared light transmitting sample supporting substrate window ,

inserting the mounting means holder into the spectrophotometer or filtometer between the infrared light source and the infrared light detector with the at least one aperture aligned with the infrared light emitted by the infrared light source to allow the passage of ~~a beam of~~ infrared light though the bacterial colony, the infrared light transmitting sample supporting substrate window and the at least one aperture and with no other material other than the bacterial colony within said at least one aperture that absorbs infrared light.